



COMPLEMENTARY PAIR ENHANCEMENT MODE MOSFET

Product Summary

Device	V _{(BR)DSS}	R _{DS(on) max}	I _D T _A = +25°C
Q1	60V	40mΩ @ V _{GS} = 10V	6.5 A
N-Channel	60 V	55mΩ @ V _{GS} = 4.5V	5.6 A
Q2	-60V	110mΩ @ V _{GS} = -10V	-3.9 A
P-Channel	-007	130mΩ @ V _{GS} = -4.5V	-3.6 A

Description and Applications

This new generation MOSFET has been designed to minimize the onstate resistance (R_{DS(ON)}) and yet maintain superior switching performance, making it ideal for high efficiency power management applications.

- DC-DC Converters
- **Power Management Functions**
- Backlighting

Features and Benefits

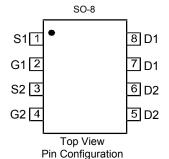
- Low Input Capacitance
- Low On-Resistance
- Fast Switching Speed
- Totally Lead-Free & Fully RoHS Compliant (Notes 1 & 2)
- Halogen and Antimony Free. "Green" Device (Note 3)
- Qualified to AEC-Q101 Standards for High Reliability

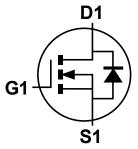
Mechanical Data

- Case: SO-8
- Case Material: Molded Plastic, "Green" Molding Compound. UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminal Connections: See Diagram
- Terminals: Finish Tin Finish annealed over Copper leadframe. Solderable per MIL-STD-202, Method 208 @3
- Weight: 0.074 grams (approximate)

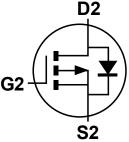












Q2 P-Channel MOSFET

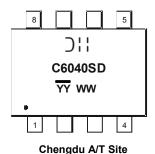
Ordering Information (Note 4)

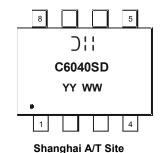
Part Number	Case	Packaging
DMC6040SSD-13	SO-8	2,500/Tape & Reel

Notes:

- 1. No purposely added lead, Fully EU Directive 2002/95/EC (RoHS) & 2011/65/EU (RoHS 2) compliant.
- 2. See http://www.diodes.com/quality/lead_free.html for more information about Diodes Incorporated's definitions of Halogen- and Antimony-free, "Green" and Lead-free.
- 3. Halogen- and Antimony-free "Green" products are defined as those which contain <900ppm bromine, <900ppm chlorine (<1500ppm total Br + Cl) and <1000ppm antimony compounds.
- 4. For packaging details, go to our website at http://www.diodes.com/products/packages.html.

Marking Information





∃; = Manufacturer's Marking C6040SD = Product Type Marking Code YYWW = Date Code Marking YY or \overline{YY} = Year (ex: 14= 2014) WW = Week (01 - 53)

YY = Date Code Marking for SAT (Shanghai Assembly/ Test site) YY = Date Code Marking for CAT (Chengdu Assembly/ Test site)



Maximum Ratings (@TA = +25°C, unless otherwise specified.)

Characteristic	Symbol	Q1	Q2	Units		
Drain-Source Voltage	V_{DSS}	60	-60	V		
Gate-Source Voltage	V_{GSS}	±20	±20	V		
Continuous Dusin Comment (Nata C) V = 40V	Steady State	T _A = +25°C T _A = +70°C	I _D	5.1 4.1	-3.1 -2.5	А
Continuous Drain Current (Note 6) V _{GS} = -10V	t<10s	T _A = +25°C T _A = +70°C	I _D	6.5 5.2	-3.9 -3.1	А
Maximum Body Diode Forward Current (Note 6)	Is	2.1	-2.1	Α		
Pulsed Drain Current (10µs pulse, duty cycle = 1	I _{DM}	28	-19	Α		
Avalanche Current (Note 7) L = 0.1mH	I _{AS}	17.2	-17.6	Α		
Avalanche Energy (Note 7) L = 0.1mH	E _{AS}	14.7	15.4	mJ		

Thermal Characteristics (@T_A = +25°C, unless otherwise specified.)

Characteristic		Symbol	Value	Units
Total Power Dissipation (Note 5)	T _A = +25°C	P_{D}	1.24	W
Total Power Dissipation (Note 5)	$T_A = +70^{\circ}C$		0.8	vv
Thormal Decistance, Junction to Ambient (Note 5)	Steady state	D	101	°C/W
Thermal Resistance, Junction to Ambient (Note 5)	t < 10s	$R_{\theta JA}$	61	
Total Power Dissipation (Note 6)	T _A = +25°C	Б	1.56	W
Total Fower Dissipation (Note 6)	T _A = +70°C	P_D	1.0	
Thormal Decistance, Junction to Ambient (Note 6)	Steady state	D	80	°C/W
Thermal Resistance, Junction to Ambient (Note 6)	t<10s	$R_{\theta JA}$	49	
Thermal Resistance, Junction to Case (Note 6)		$R_{ heta JC}$	14.7	
Operating and Storage Temperature Range		T _{J,} T _{STG}	-55 to +150	°C

Electrical Characteristics N-Channel Q1 (@TA = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 8)					•	
Drain-Source Breakdown Voltage	BV _{DSS}	60	_	_	V	$V_{GS} = 0V, I_D = 250\mu A$
Zero Gate Voltage Drain Current	I _{DSS}	_	_	1	μΑ	$V_{DS} = 48V, V_{GS} = 0V$
Gate-Source Leakage	I _{GSS}	_	_	±100	nA	$V_{GS} = \pm 20V, V_{DS} = 0V$
ON CHARACTERISTICS (Note 8)						
Gate Threshold Voltage	V _{GS(th)}	1	_	3	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
Static Drain-Source On-Resistance	_	_	33	40	mΩ	V _{GS} = 10V, I _D = 8A
Static Drain-Source On-Resistance	R _{DS (ON)}	_	37	55	11122	V _{GS} = 4.5V, I _D = 5A
Diode Forward Voltage	V _{SD}	_	0.7	1.2	V	V _{GS} = 0V, I _S = 1A
DYNAMIC CHARACTERISTICS (Note 9)					•	
Input Capacitance	C _{iss}	_	1130	_		V _{DS} = 15V, V _{GS} = 0V f = 1.0MHz
Output Capacitance	Coss	_	69	_	pF	
Reverse Transfer Capacitance	C _{rss}	_	42	_		
Gate Resistance	R_G	_	1.7	_	Ω	$V_{DS} = 0V, V_{GS} = 0V, f = 1.0MHz$
Total Gate Charge (V _{GS} = 10V)	Qg	_	20.8	_		
Total Gate Charge (V _{GS} = 4.5V)	Qg	_	9.4	_	nC	\\ -20\\ -4.24
Gate-Source Charge	Q _{gs}	_	3.3	_	IIC	$V_{DS} = 30V, I_D = 4.3A$
Gate-Drain Charge	Q _{gd}	_	3.0	_		
Turn-On Delay Time	t _{D(on)}	_	3.6	_		$V_{GS} = 10V, V_{DD} = 30V, R_{G} = 6\Omega,$
Turn-On Rise Time	t _r	_	1.8	_	0	
Turn-Off Delay Time	t _{D(off)}	_	20.1	_	nS	I _D = 4.3A
Turn-Off Fall Time	t _f	_	4.3	_		
Body Diode Reverse Recovery Time	t _{rr}	_	14.2	_	nS	I _S = 4.3A, dI/dt = 100A/µs
Body Diode Reverse Recovery Charge	Qrr	_	7.5	_	nC	I _S = 4.3A, dl/dt = 100A/µs

Notes: 5. Device mounted on FR-4 substrate PC board, 2oz copper, with minimum recommended pad layout.

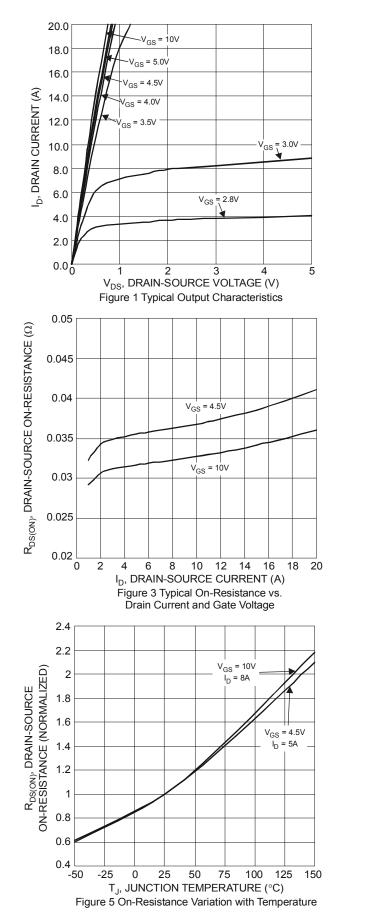
6. Device mounted on FR-4 substrate PC board, 2oz copper, with 1inch square copper plate.

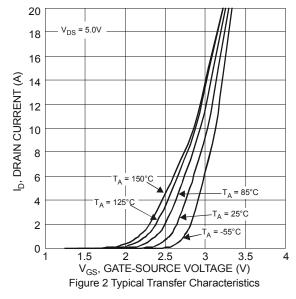
7. UIS in production with L = 0.1mH, starting $T_A = +25$ °C.

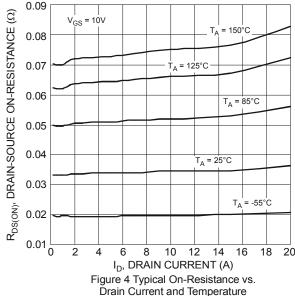
8. Short duration pulse test used to minimize self-heating effect.

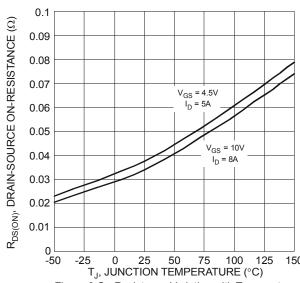
9. Guaranteed by design. Not subject to product testing.













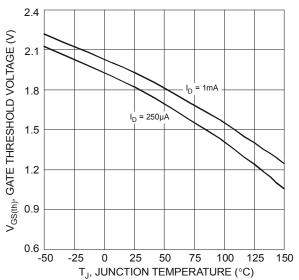
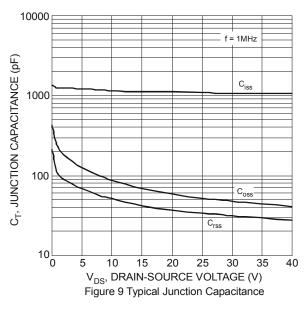
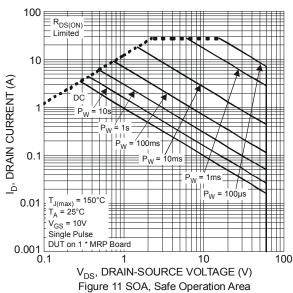
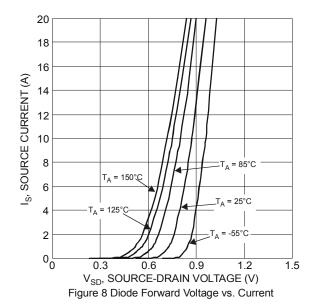
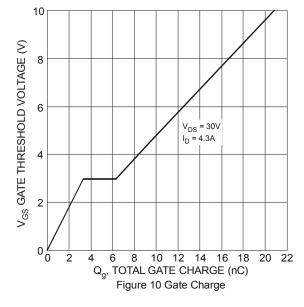


Figure 7 Gate Threshold Variation vs. Ambient Temperature

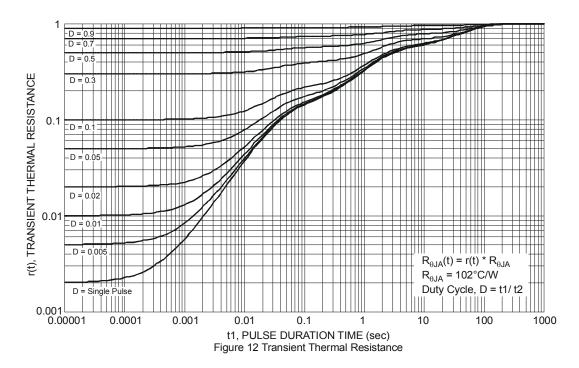












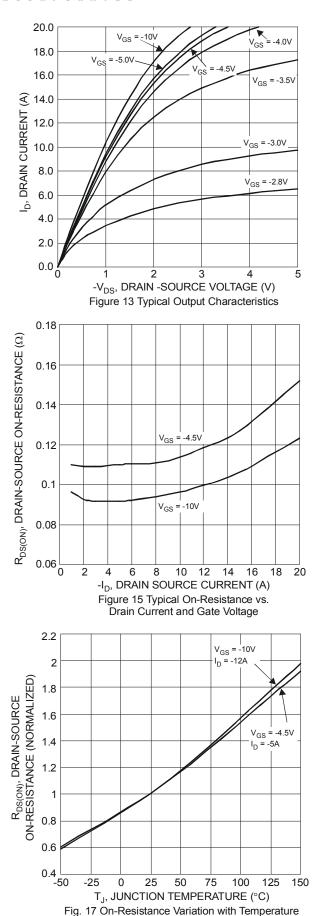
Electrical Characteristics P-Channel Q2 (@T_A = +25°C, unless otherwise specified.)

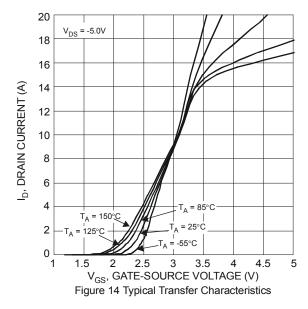
Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 8)						
Drain-Source Breakdown Voltage	BV_{DSS}	-60	_	_	V	$V_{GS} = 0V, I_D = -250\mu A$
Zero Gate Voltage Drain Current	I _{DSS}	_	_	-1	μΑ	V _{DS} = -48V, V _{GS} = 0V
Gate-Source Leakage	I _{GSS}	_	_	100	nA	$V_{GS} = \pm 16V, V_{DS} = 0V$
ON CHARACTERISTICS (Note 8)						
Gate Threshold Voltage	$V_{GS(th)}$	-1		-3	V	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$
Static Drain-Source On-Resistance	J		86	110	mΩ	$V_{GS} = -10V, I_D = -4.5A$
Static Dialii-Source Off-Resistance	R _{DS (ON)}		98	130	11177	$V_{GS} = -4.5V, I_D = -3.5A$
Diode Forward Voltage	V_{SD}	_	-0.7	-1.2	V	$V_{GS} = 0V, I_{S} = -1A$
DYNAMIC CHARACTERISTICS (Note 9)						
Input Capacitance	C _{iss}		1030			V _{DS} = -30V, V _{GS} = 0V, f = 1.0MHz
Output Capacitance	Coss		49.1		pF	
Reverse Transfer Capacitance	C_{rss}		38.7			
Gate Resistance	R_G		13.6	_	Ω	$V_{DS} = 0V, V_{GS} = 0V, f = 1.0MHz$
Total Gate Charge (V _{GS} = -4.5V)	Q_g		9.5			
Total Gate Charge (V _{GS} = -10V)	Q_g		19.4	_	nC	V _{DS} = -30V, I _D = -5A
Gate-Source Charge	Q_{gs}		2.3		IIC	V _{DS} = -30V, I _D = -5A
Gate-Drain Charge	Q_{gd}		3.6			
Turn-On Delay Time	$t_{D(on)}$	_	3.7	_		
Turn-On Rise Time	t _r	_	6.3	_	nS	$V_{GS} = -10V$, $V_{DS} = -30V$, $R_{GEN} = 6\Omega$,
Turn-Off Delay Time	$t_{D(off)}$	_	58.7	_	113	I _D = -5A
Turn-Off Fall Time	t _f		26.1			
Body Diode Reverse Recovery Time	t _{rr}	_	14.85	_	nS	I _S = -5A, dI/dt = 100A/μs
Body Diode Reverse Recovery Charge	Q _{rr}	_	8.8	_	nC	I _S = -5A, dI/dt = 100A/µs

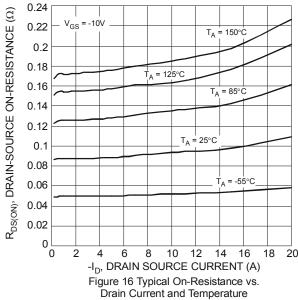
Notes: 5. Device mounted on FR-4 substrate PC board, 2oz copper, with minimum recommended pad layout.

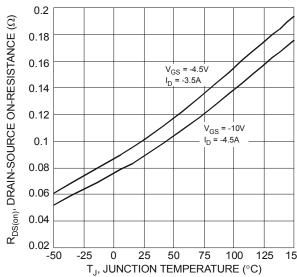
Device mounted on FR-4 substrate PC board, 20z copper, with minimum recommended be
Device mounted on FR-4 substrate PC board, 20z copper, with 1inch square copper plate.
UIS in production with L = 0.1mH, starting T_A = +25°C.
Short duration pulse test used to minimize self-heating effect.
Guaranteed by design. Not subject to product testing.













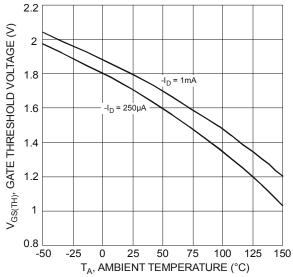
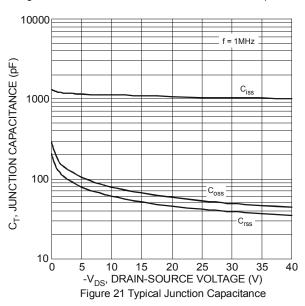
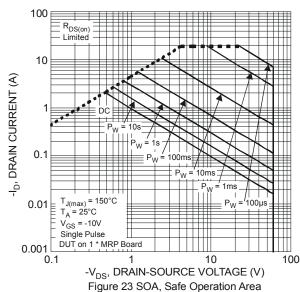
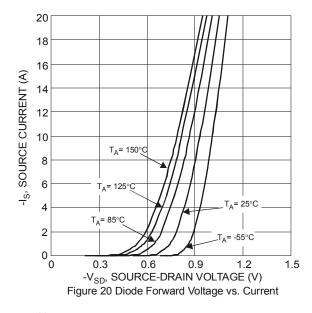
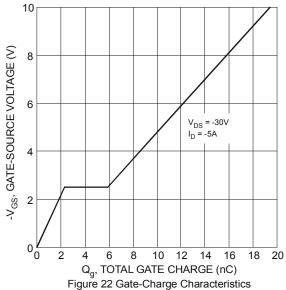


Figure 19 Gate Threshold Variation vs. Ambient Temperature





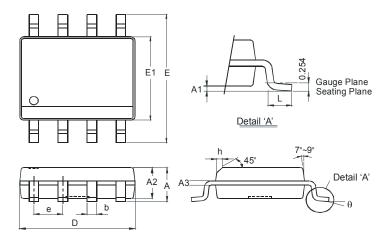






Package Outline Dimensions

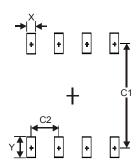
Please see AP02002 at http://www.diodes.com/datasheets/ap02002.pdf for the latest version.



SO-8						
Dim	Min	Max				
Α	1	1.75				
A 1	0.10	0.20				
A2	1.30	1.50				
A3	0.15	0.25				
b	0.3	0.5				
D	4.85	4.95				
Е	5.90	6.10				
E1	3.85	3.95				
е	1.27 Typ					
h	-	0.35				
L	0.62	0.82				
θ	0°	8°				
All Dimensions in mm						

Suggested Pad Layout

Please see AP02001 at http://www.diodes.com/datasheets/ap02001.pdf for the latest version.



Dimensions	Value (in mm)
Х	0.60
Y	1.55
C1	5.4
C2	1.27



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